



Data sheet acquired from Harris Semiconductor SCHS100

CD40110B Types

CMOS Decade Up-Down Counter/Latch/Display Driver

High-Voltage Type (20-V Rating)



Features:

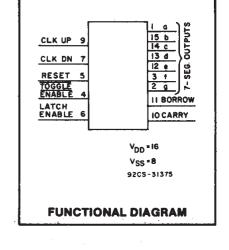
- Separate clock-up and clock-down lines-
- Capable of driving common cathode LEDs and other displays directly
- Allows cascading without any external circuitry
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 µA at 18 V over full packagetemperature range; 100 nA at 18 V and 25° C

■ CD40110B is a dual-clocked up/down counter with a special preconditioning circuit that allows the counter to be clocked, via positive going inputs, up or down regardless of the state or timing (within 100 ns typ.) of the other clock line.

The clock signal is fed into the control logic and Johnson counter after it is preconditioned. The outputs of the Johnson counter (which include anti-lock gating to avoid being locked at an illegal state) are fed into a latch. This data can be fed directly to the decoder through the latch or can be strobed to hold a particular count while the Johnson counter continues to be clocked. The decoder feeds a seven-segment bipolar output driver which can source up to 25 mA to drive LEDs and other displays such as lowvoltage fluorescent and incandescent lamps.

A short durating negative-going pulse appears on the BORROW output when the count changes from 0 to 9 or the CARRY output when the count changes from 9 to 0. At the other times the BORROW and CARRY outputs are a logic 1.

The CARRY and BORROW outputs can be tied directly to the clock-up and clock-down lines respectively of another CD40110B for easy cascading of several counters.



- Noise margin (full package-temperature range) =
 - 1 V at V_{DD} = 5 V 2 V at V_{DD} = 10 V

 - 2.5 V at VDD = 15 V
- 5 V, 10 V and 15 V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices".

Applications:

- Rate comparators
- General counting applications where display is desired
- Up-down counting applications where input pulses are random in nature

The CD40110B types are supplied in 16-lead dual-in-line ceramic packages (D and F suffixes), and 16-lead dual-inline plastic package (E suffix), and also available in chip form, (H suffix).

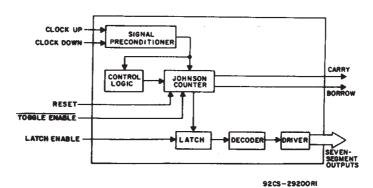


Fig. 1 - Functional diagram.



MAXIMUM RATINGS, Absolute-Maximum Values:DC SUPPLY-VOLTAGE RANGE, (VDD)-0.5V to +20VVoltages referenced to V_{SS} Terminal)-0.5V to +20VINPUT VOLTAGE RANGE, ALL INPUTS-0.5V to $V_{DD} +0.5V$ DC INPUT CURRENT, ANY ONE INPUT $\pm 10mA$ POWER DISSIPATION PER PACKAGE (PD):500mWFor $T_A = -55^{\circ}C$ to $+100^{\circ}C$ 500mWDEVICE DISSIPATION PER OUTPUT TRANSISTORDerate Linearity at $12mW/^{\circ}C$ to 200mWOPERATING-TEMPERATURE RANGE (T_A) $-55^{\circ}C$ to $+125^{\circ}C$ STORAGE TEMPERATURE RANGE (T_{St}) $-65^{\circ}C$ to $+150^{\circ}C$ LEAD TEMPERATURE (DURING SOLDERING): $-65^{\circ}C$ to $+150^{\circ}C$ At distance $1/16 \pm 1/32$ inch $(1.59 \pm 0.79mm)$ from case for 10s max $+265^{\circ}C$

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

	CHARACTERISTIC	er († 1864) 1860 – Primario Landon, september 1861 – Primario Landon, september († 1868)	V _{DD}	LIM MIN.	MAX.	UNITS
Supply-Voltage Range (For TA	= Full Package Temperat	ure Range)	_	3	18	V
Clock Input Frequency (Sum of CLUP & CLDN Freqs.	fol [*]	e <mark>dir talah an Sebilah da</mark> Sebilah dan Sebilah dan Sebilah dan Sebilah dan sebilah dan	5 10 15		1 3 5	MHz
Clock Pulse Width tw			5 10 15	110 40 30	111	
Latch Enable Pulse Width	N	100 Maria (1900)	5 10 15	110 30 24		ns
Reset Removal-Time		The second secon	5 10 15	550 200 130		erita in periodici di serie d Serie di serie di se
Reset Pulse Width			5 10 15	350 170 120	=	

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STATIC ELECTRICAL CHARACTERISTICS

		Cond	tions				34-						
Characteristic				LIMITS AT INDICATED TEMPERATURES (°C)						Units			
	IOH	VOH	VIN	VDD		40		.402	841-	+25			
-	(mA)	(V)	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.		
Outron to Doutro	l _	_	_	5	5	5	150	150		0.04	5		
Quiescent Device				10	10	10	300	300	_	0.04	10	μA	
Current Max. I _{DD}		_		15	20	20	600	600		0.04	20	μΑ	
Max. IDD	_			20	100	100	3000	3000		0.08	100		
-										_			
Output Voltage			0,5	5	0.05					0	0.05	, ,	
Low-Level			0,10	10			05			0	10.05	V	
Max. VOL		_	0,15	15		0.	05			0	0.05		
		_ `	0,5	5		_		_	_	4.55			
High-Level			0,10	10					_	9.55		v	
Min. V _{OH}			0,15	15						14.55		'	
· · · · · · · · · · · · · · · · · · ·			0,13	,,,				l		17.00			
Input Low Voltage	_	0.5, 3.8		5		1	.5				1.5		
Max. VIL		1, 8.8	_	10		3				_	3	V	
		1.5, 13.8		15			4	-		_	4		
1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 -								-					
Input High Voltage		0.5, 3.8		5		3	.8		3.5				
Min. VIH		1, 8.8		10			7		7			V	
<u> </u>		1.5, 13.8		15		1	1		11				
	l	ļ		1 1	١ ,	^				4.5			
	-					.9		<u>4</u>	3.9	4.5			
	-5	-	_			65		.7	3.7	4.3			
	-10			5	3.55 3.65 3.5 3.5 3.45 3.35 3.4 3.3		3.65 3.6	4.25 4.15		-			
	-15 -20		=	-				3.45	4.15	 	1		
	-25		-					3,4	3.9	+=			
	-25			10		.4 75		.s 85	8.75	9.5			
7-Segment Outputs						45		55	8.55	9.3			
Output Drive	-10		_		1 1		42		.5	8.5	9.25	_	
Voltage, High	-15	_				.4		47	8.47	9.2		V	
Min. VOH	-20		_	†	8.4		8.40		8.45	9.1		†	
, VOR	-25	 	_	† '		.3		25	8.3	9			
				 		3.8		3.9	13.8	14.5			
	-5			1		.65		.75	13.75	14.35	_		
	-10			1 15	13	3.6		.72	13.72	14.3			
	-15	l – –	_	1 '3	13	3.6	10	3.7	13.7	14.2			
	-20]		3.6		3.6	13.65	14.1			
	-25	<u> </u>	-		13	3.3	13	.25	13.3	14.0			
7-Segment Outputs			1		*	ł						1	
Output Low	1	0.4	0,5	5	1.28	1.22	0.84	0.72	1	2	 -		
(Sink) Current	<u> </u>	0.5	0, 10	10	3.2	3	2.2	1.8	2.6	5.2			
Min. IOL	-	1.5	0, 15	15	8.4	8	5.6	4.8	6.8	13.6	-	}	
	1			1	 						1	Ì	
Carry Outputs Output Low (Sink) Current		0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1			
		0.5	0, 10	10	1.6	1.5	1.1	0.9	1.3	2.6		mA.	
Min. IOL		1.5	0, 15	15	4.2	4	2.8	2.4	3.4	6.8	-		
	+	 		 	 							+	
Output High		4.6	0, 5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1]	
(Source) Current		2.5	0, 5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2]	
Min. IOH	_	9.5	0, 10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	_	1	
	_	13.5	0, 15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	_]	
Input Current Max. I _{IN}	_	0, 18	0, 18	18	±0.1	±0.1	±1	±1	_	±10 ⁻⁵	±0.1	μΑ	

^{■ 0(10} µA)



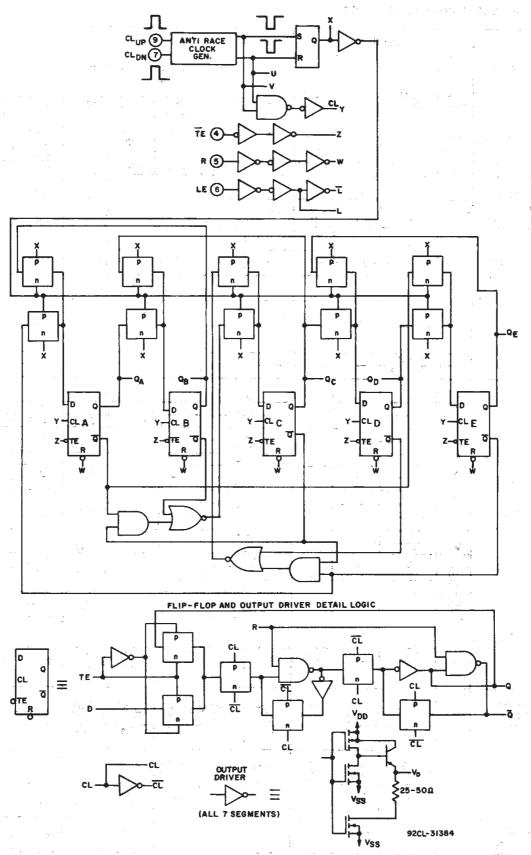


Fig. 2 - Logic diagram with flip-flop and output-driver details. (cont'd on page 5)



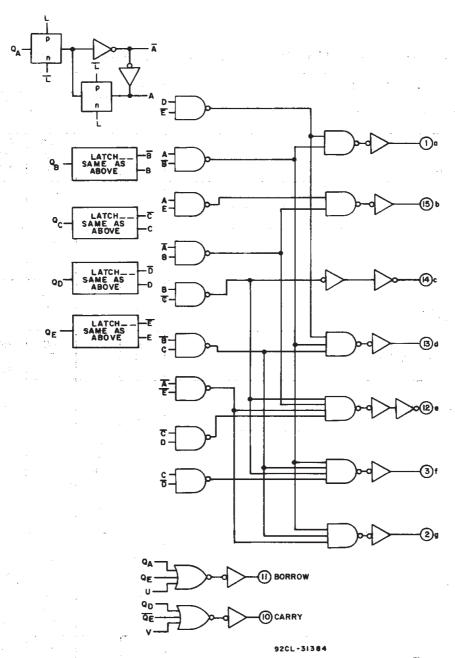
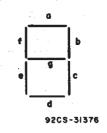
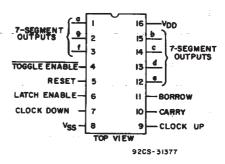


Fig. 2 - Logic diagram with flip-flop and output-driver details.

DISPLAY SEGMENTS



TERMINAL ASSIGNMENT





DYNAMIC ELECTRICAL CHARACTERISTICS at T_A = 25° C, Input t_r , t_f = 20 ns, C_L = 50 pF, R_L = 200 k Ω

CHARACTERISTIC			LIMITS			UNITS
		(V)	MIN.	TYP.	MAX.	
Clock Up/Clock Down						
		5	_	300	600	
Propagation Delay Time: Clock to Carry or Borrow	tPLH, tPHL	10 15		100 70	200 140	
	ירנה ידהב					
Clock to Segment	tpLH, tpHL	5 10	_	925 360	1850 720	ns
	4 EID 4 1E	15	_	250	500	
		5		55	110	
Minimum Clock Pulse Width		10	_	20 15	40 30	
	·	15		15	30	
Maximum Clark Innut Francisco	· fai	5 10	1 3	2.5 6	_	MHz
Maximum Clock Input Frequency (Sum of CLUP & CLDN F)	fCL	15	5	8.5	_	WIFIZ
		5		175	350	
Minimum Toggle Enable Pulse Width		10		75	150	
	······································	15		55	110	
		. 5	_	55	110	
Minimum Latch Enable Pulse Width		10 15	_	15 12	30 24	
			115	000		
Output Pulse Width:		5 10	115 60	230 120	=	
Carry		15	40	75		ns
		5	140	275	-	113
Borrow		10 15	65 45	130 85	_	
			73		<u> </u>	
Transition Time:	tTLH, tTHL	5 10		85 45	170 90	
Carry or Borrow	יובחי יוחב	15	_	30	60	
		5	_	100		
Minimum Delay Time		10	_	80	-	
Between CLUP & CLDN		15		60		
Marine Clark Rice of Fell Time	+ 01 + 01	5 10		_	15 15	μs
Maximum Clock Rise or Fall Time	trCL, trCL	15	- =	=	15	μο
Reset			<u>. </u>	!	<u> </u>	
Neset		5		650	1300	
Propagation Delay Time	tPLH, tPHL	10	_	350	700	
Reset to Output		15	_	160	320	
<u></u>		5		-275	0	25
Minimum Reset Removal Time		10 15		-100 -65	0	กร
2				-	250	
Minimum Reset Pulse Width		5 10		175 85	350 170	
*		15.	_	60	120	



TRUTH TABLE

CLOCK UP *	CLOCK DOWN *	LATCH ENABLE	TOGGLE ENABLE	RESET	COUNTER	DISPLAY	
[X	0	0	0	Increments by 1	Follows Counter	
X		0	. 0	0	Decrements by 1	Follows Counter	
		X	* X	0	No Change	No Change	
X	X	1	X	1	Goes to 00000	Remains Fixed	
X	X	0	х	1 sevices	Goes to 00000	Follows Counter (Display = 1/7)	
X	Х	x	1	0	Inhibited	Remains Fixed	
	×	1	0	0	Increments by 1	Remains Fixed	
: X		1	0	.0	Decrements by 1	Remains Fixed	

X = Don't Care

^{*} Typically 100 ne between clock-up and clock-down positive transitions are required to ensure proper counting.

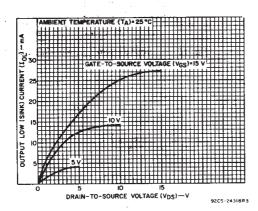


Fig. 3 - Typical carry or borrow output low (sink) current characteristics.

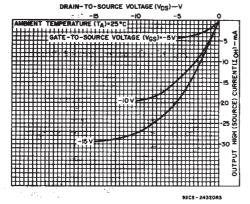


Fig. 5 - Typical carry or borrow output high (source) current characteristics.

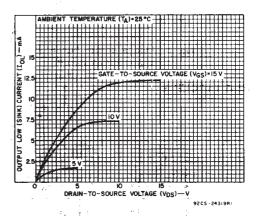


Fig. 4 - Minimum carry or borrow output low (sink) current characteristics.

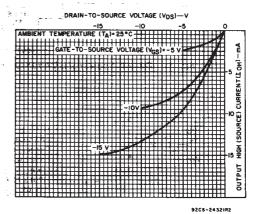


Fig. 6 - Minimum carry or borrow output high (source) current characteristics.

^{1 =} High State

^{0 =} Low State



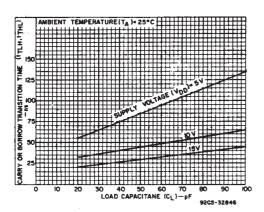


Fig. 7 - Typical carry or borrow transition time vs. load capacitance.

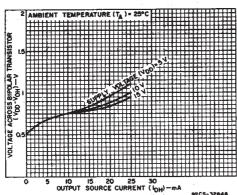


Fig. 9 - Voltage across bipolar transistor vs. output source current.

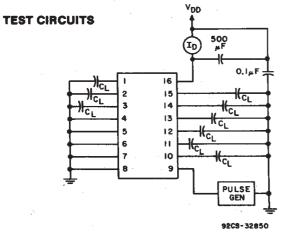


Fig. 11 - Dynamic power dissipation test circuit.

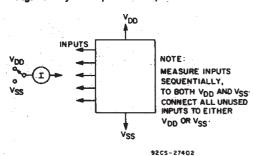


Fig. 13 - Input current.

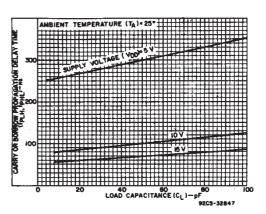


Fig. 8 - Typical carry or borrow propagation delay time vs. load capacitance.

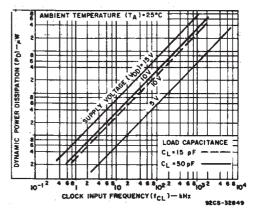


Fig. 10 - Typical dynamic power dissipation vs. frequency.

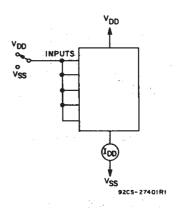


Fig. 12 - Quiescent device current.

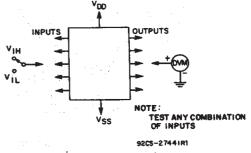


Fig. 14 - Input voltage.



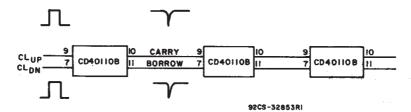
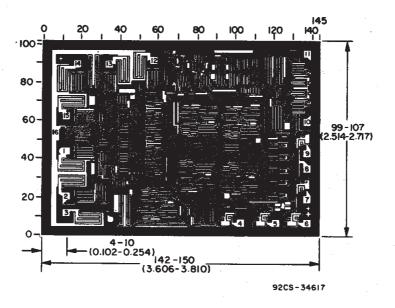


Fig. 15 - Cascading diagram.



Dimensions and pad layout for CD40110B.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10⁻³ inch).



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